Device Modeling Report

COMPONENTS: Power MOSFET (Model Parameters)
PART NUMBER: 2SJ656
MANUFACTURER: SANYO
Body Diode (Model Parameters) / ESD Protection Diode

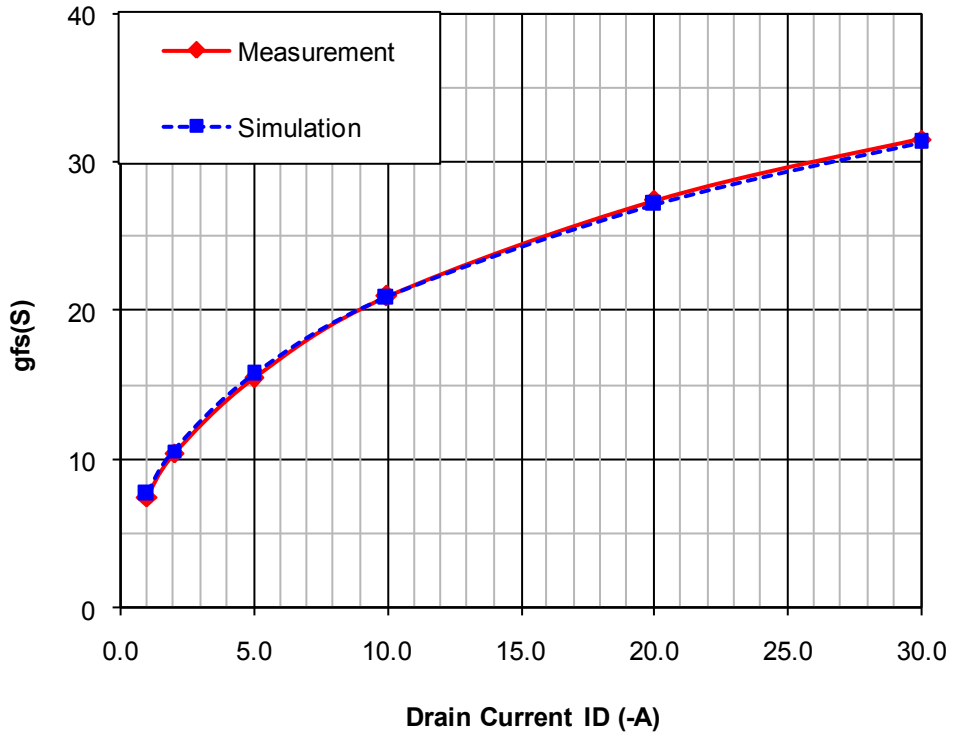
Bee Technologies Inc.

MOSFET MODEL

PSpice model parameter	Model description
LEVEL	
L	Channel Length
W	Channel Width
KP	Transconductance
RS	Source Ohmic Resistance
RD	Ohmic Drain Resistance
VTO	Zero-bias Threshold Voltage
RDS	Drain-Source Shunt Resistance
TOX	Gate Oxide Thickness
CGSO	Zero-bias Gate-Source Capacitance
CGDO	Zero-bias Gate-Drain Capacitance
CBD	Zero-bias Bulk-Drain Junction Capacitance
MJ	Bulk Junction Grading Coefficient
PB	Bulk Junction Potential
FC	Bulk Junction Forward-bias Capacitance Coefficient
RG	Gate Ohmic Resistance
IS	Bulk Junction Saturation Current
N	Bulk Junction Emission Coefficient
RB	Bulk Series Resistance
PHI	Surface Inversion Potential
GAMMA	Body-effect Parameter
DELTA	Width effect on Threshold Voltage
ETA	Static Feedback on Threshold Voltage
THETA	Mobility Modulation
KAPPA	Saturation Field Factor
VMAX	Maximum Drift Velocity of Carriers
XJ	Metallurgical Junction Depth
UO	Surface Mobility

Transconductance Characteristic

Circuit Simulation Result

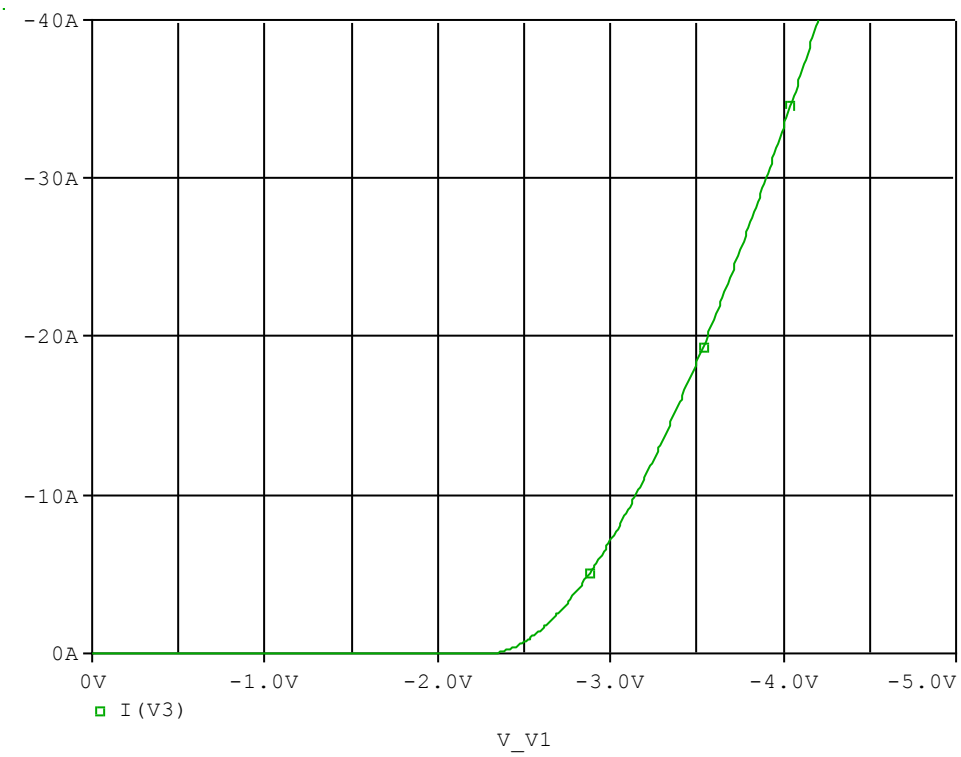


Comparison table

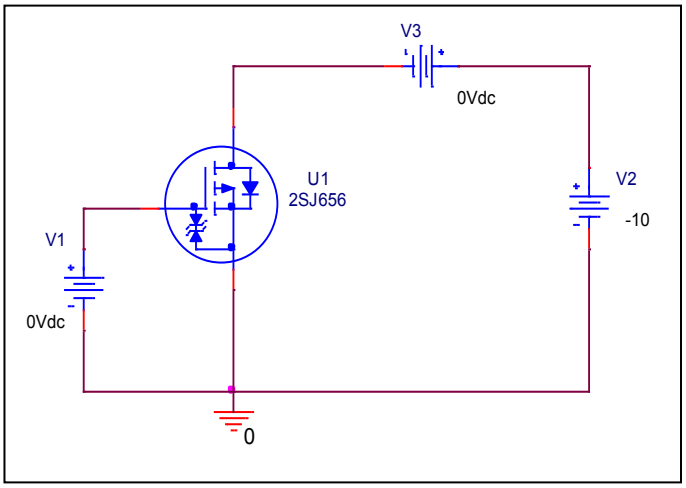
-Id(A)	gfs(S)		Error (%)
	Measurement	Simulation	
1	7.500	7.721	2.94
2	10.400	10.580	1.73
5	15.500	15.757	1.66
10	21.000	20.925	-0.36
20	27.500	27.236	-0.96
30	31.600	31.417	-0.58

Vgs-Id Characteristic

Circuit Simulation result

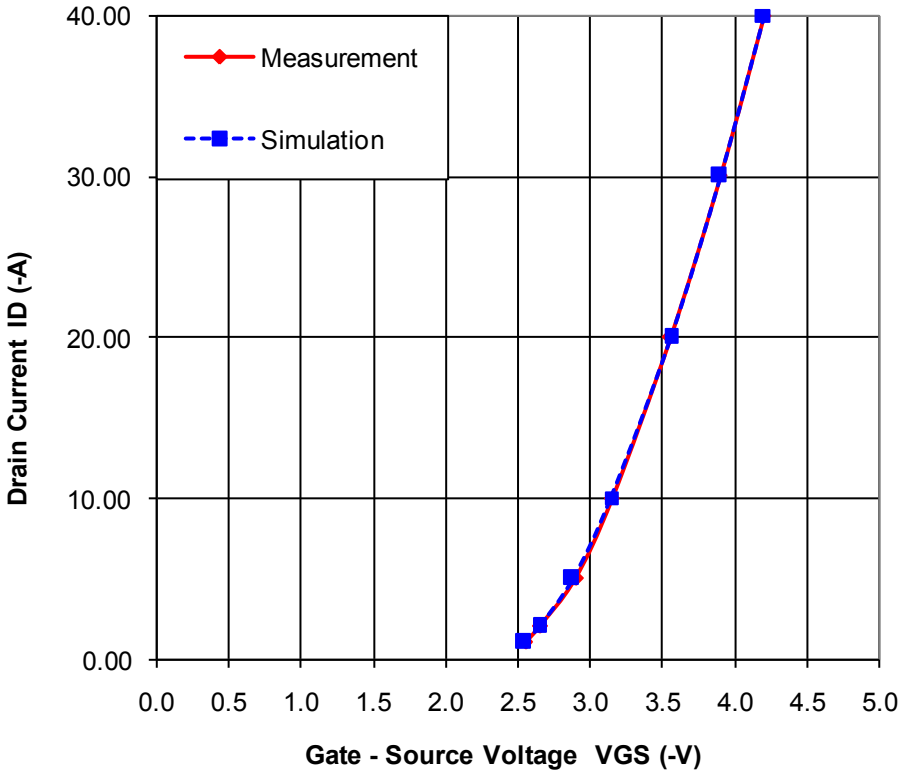


Evaluation circuit



Comparison Graph

Circuit Simulation Result

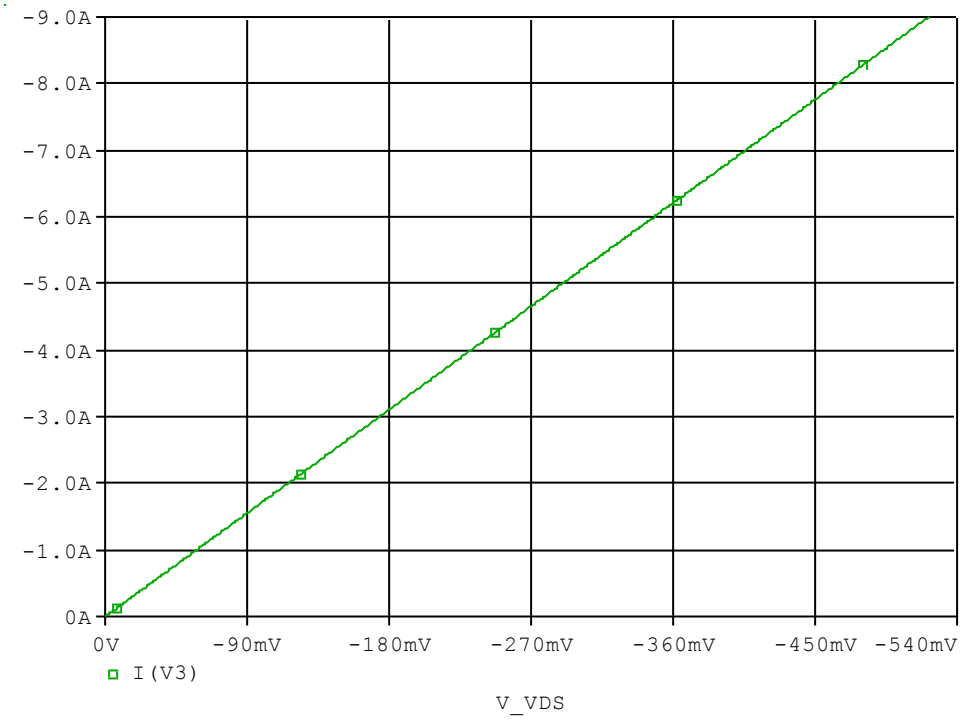


Simulation Result

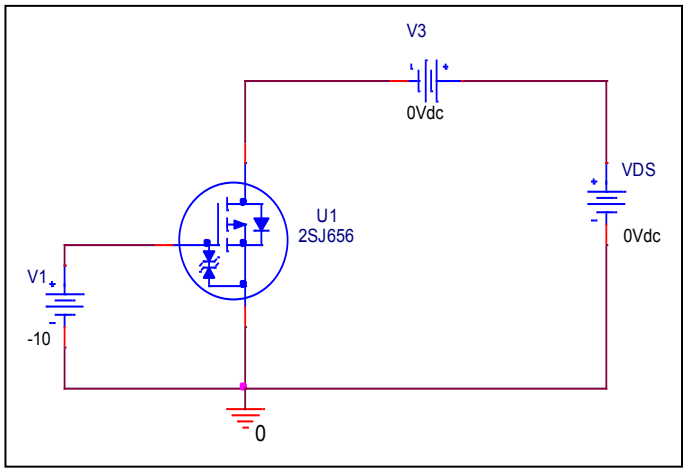
$-I_D$(A)	$-V_{GS}$(V)		Error (%)
	Measurement	Simulation	
1	2.550	2.539	-0.42
2	2.650	2.648	-0.06
5	2.900	2.875	-0.87
10	3.150	3.146	-0.12
20	3.550	3.559	0.26
30	3.900	3.900	-0.01
40	4.200	4.202	0.05

Rds(on) Characteristic

Circuit Simulation result



Evaluation circuit

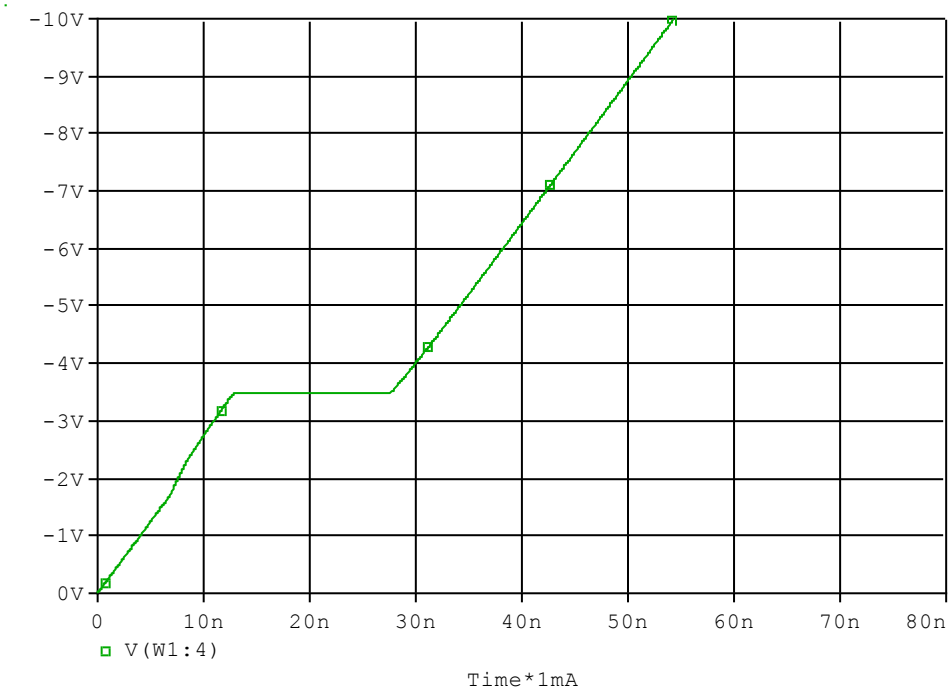


Simulation Result

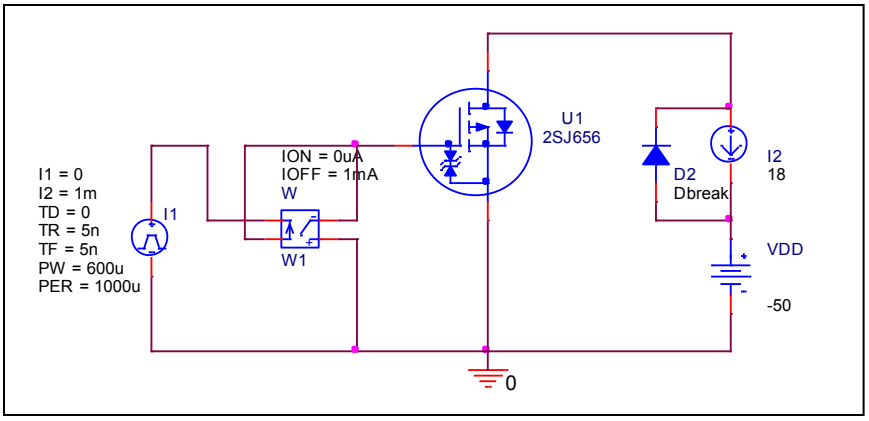
I_D=--9A, V_{GS}=-10V		Measurement	Simulation	Error (%)
R_{DS} (on)	mΩ	58.000	58.000	0.00

Gate Charge Characteristic

Circuit Simulation result



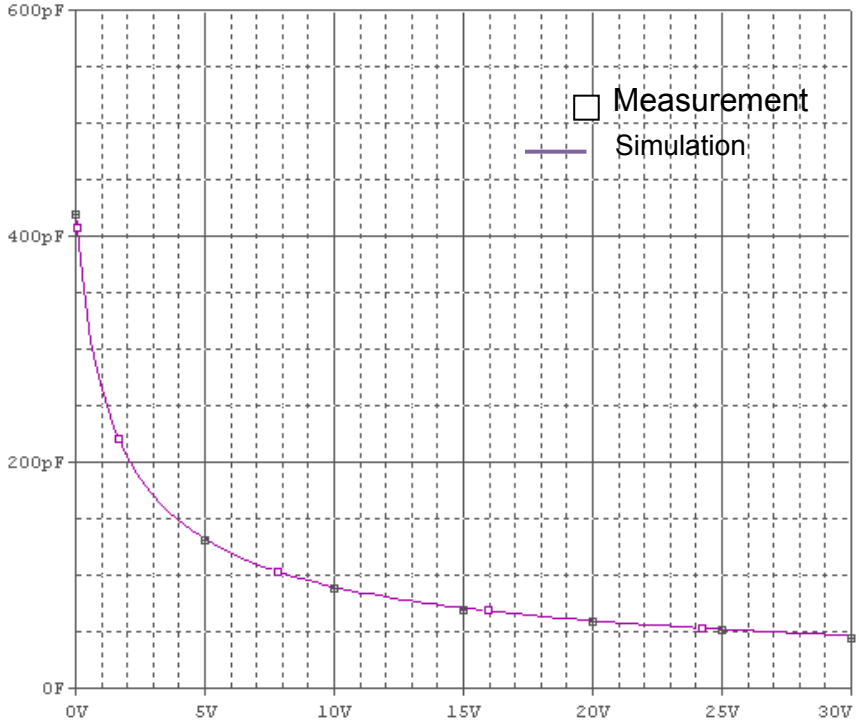
Evaluation circuit



Simulation Result

V_{DD}=-50V,I_D=-18A ,V_{GS}=-10V		Measurement	Simulation	Error (%)
Qgs	nC	12.800	12.797	-0.02
Qgd	nC	14.700	14.755	0.37
Qg	nC	74.000	54.341	-26.57

Capacitance Characteristic

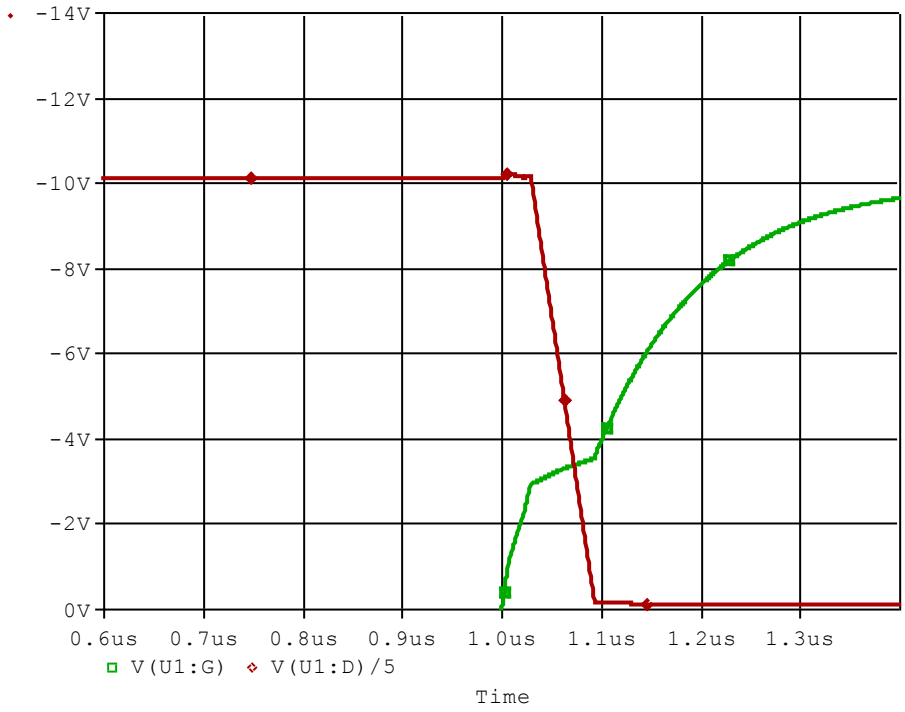


Simulation Result

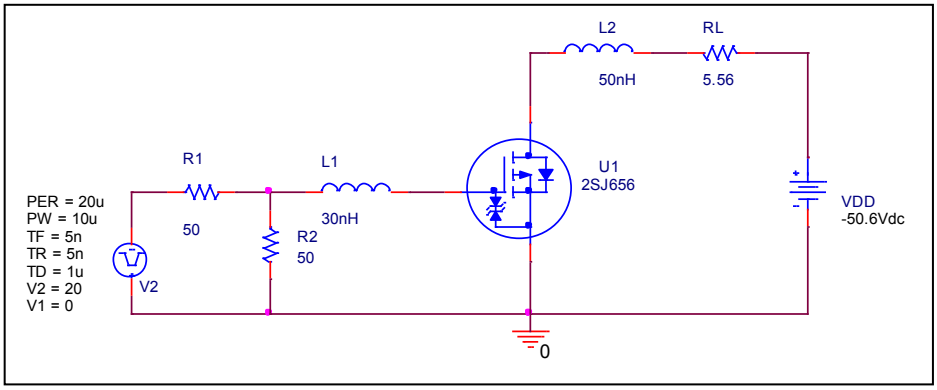
V_{SD}(V)	Cbd(pF)		Error(%)
	Measurement	Simulation	
0	420.000	420.000	0.000
5	132.000	131.750	-0.189
10	89.000	89.765	0.860
15	71.000	70.860	-0.197
20	60.000	59.700	-0.500
25	53.000	52.185	-1.538
30	46.000	46.716	1.557

Switching Time Characteristic

Circuit Simulation result



Evaluation circuit

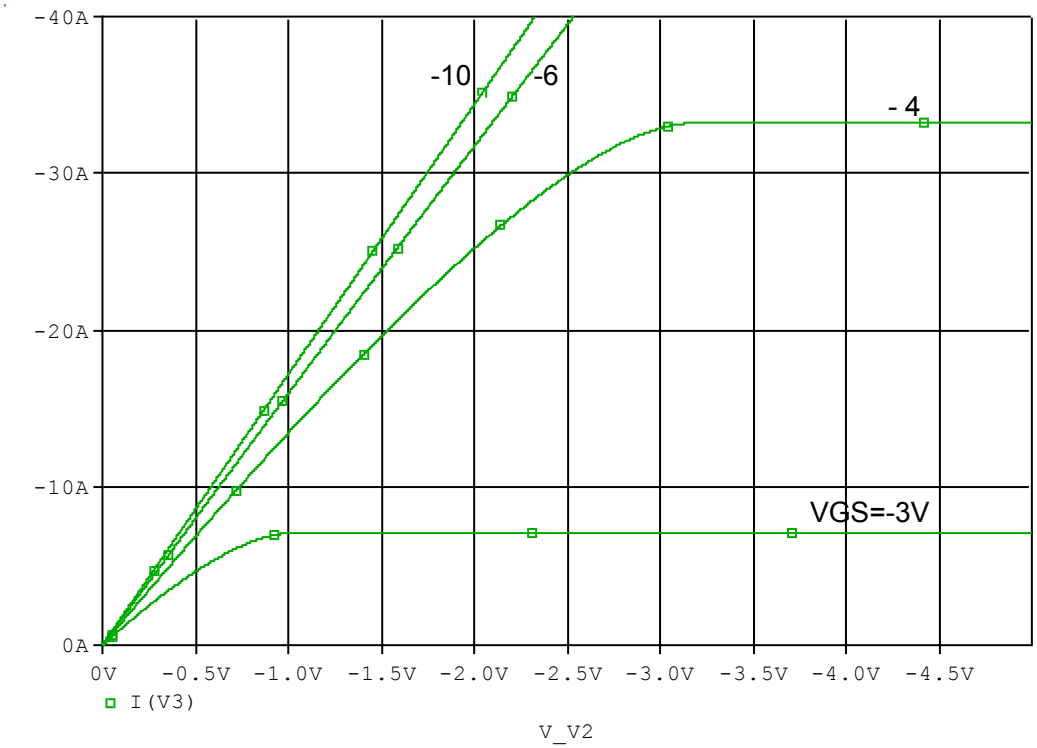


Simulation Result

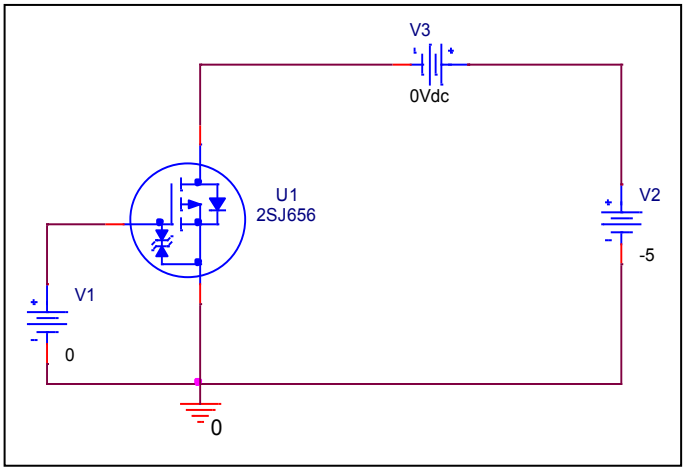
I_D=-9A, V_{DD}=-50V V_{GS}=0/-10V		Measurement	Simulation	Error(%)
td(on)	ns	30.000	30.013	0.04

Output Characteristic

Circuit Simulation result

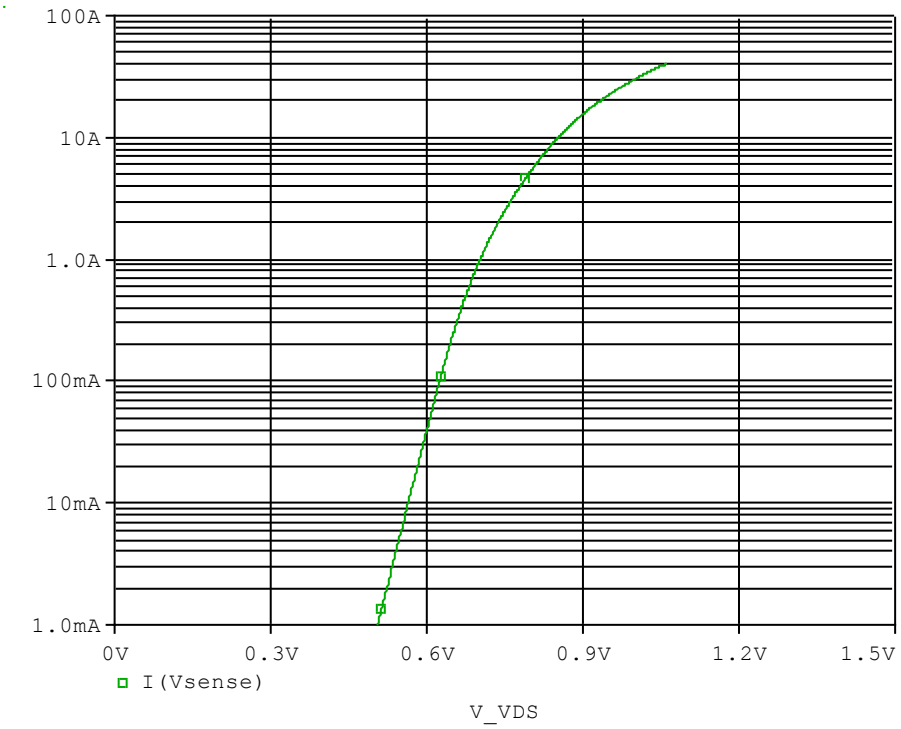


Evaluation circuit

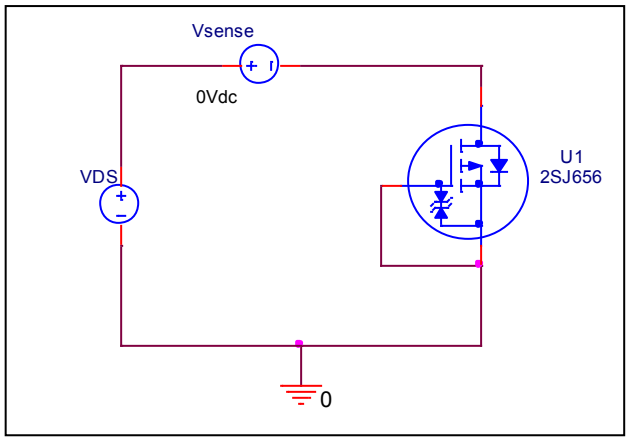


BODY DIODE SPICE MODEL
Forward Current Characteristic

Circuit Simulation Result

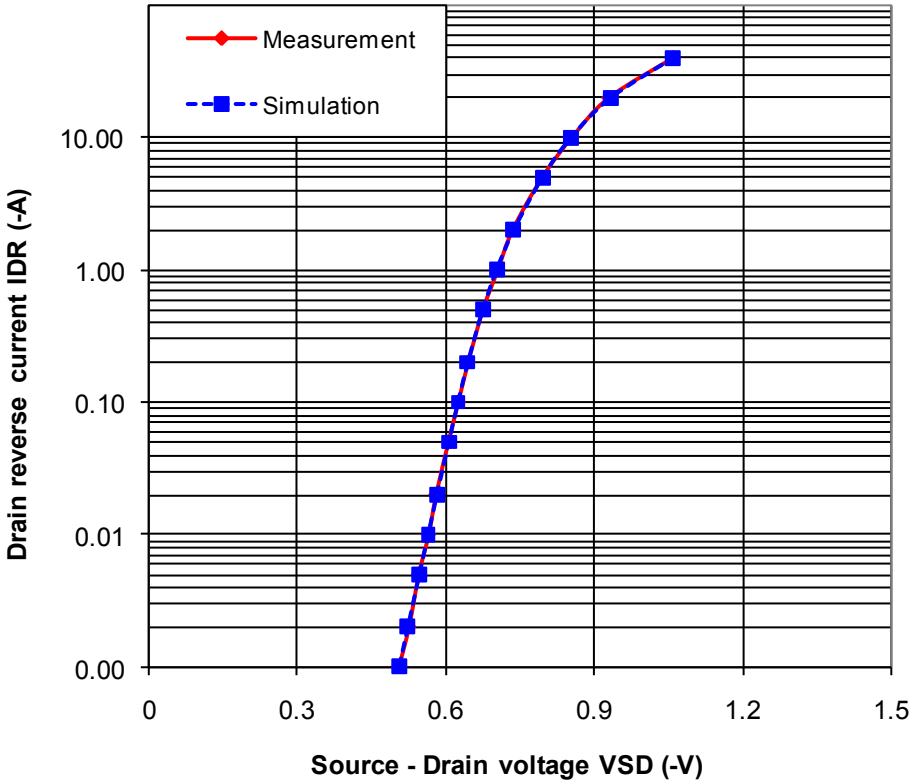


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

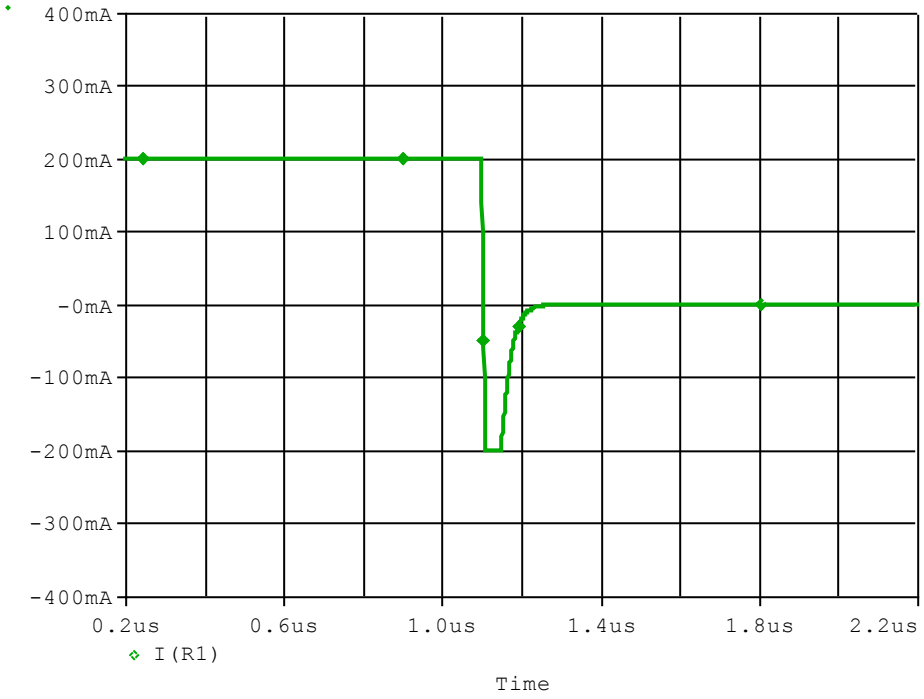


Simulation Result

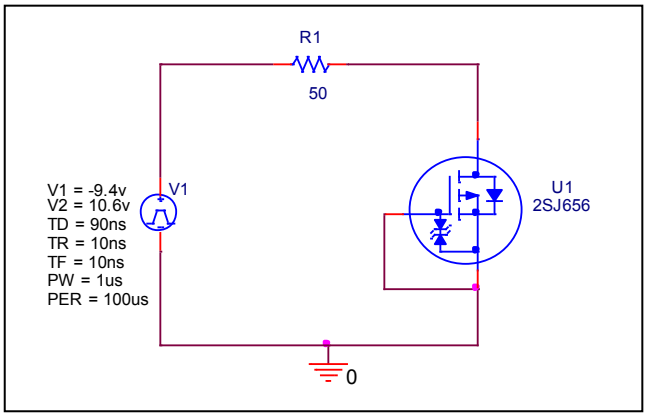
IDR(-A)	VSD(-V)		%Error
	Measurement	Simulation	
0.001	0.5050	0.5055	0.10
0.01	0.5650	0.5641	-0.16
0.1	0.6250	0.6246	-0.07
1	0.7050	0.7025	-0.36
2	0.7350	0.7372	0.29
5	0.7950	0.7952	0.02
10	0.8550	0.8527	-0.27
20	0.9300	0.9331	0.33
40	1.0600	1.0590	-0.09

Reverse Recovery Characteristic

Circuit Simulation Result



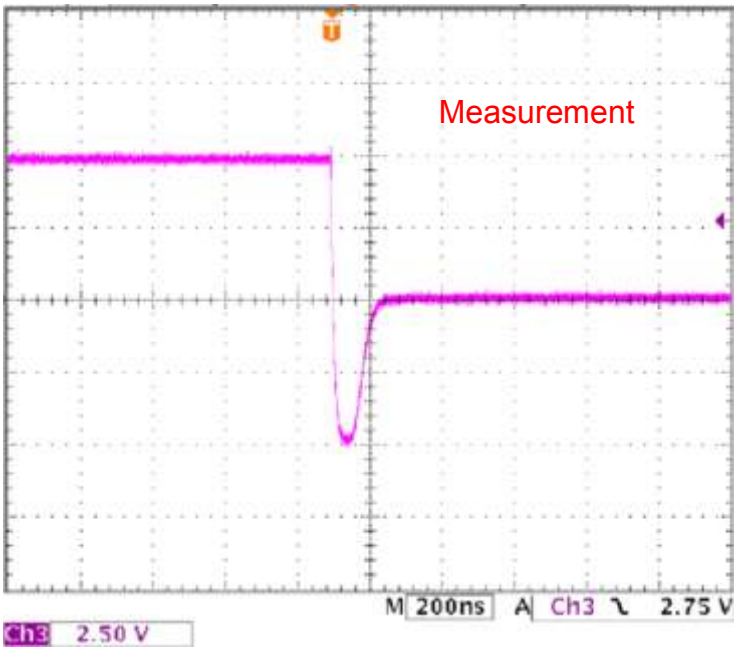
Evaluation Circuit



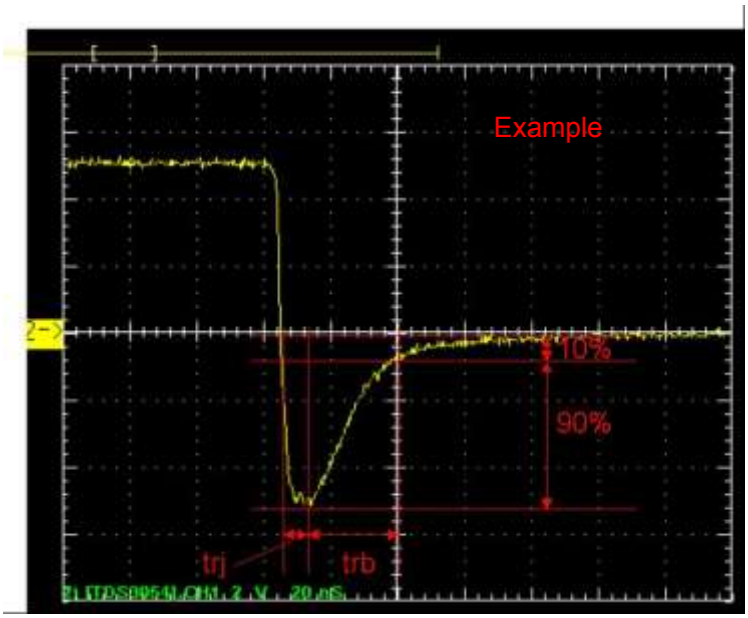
Compare Measurement vs. Simulation

		Measurement	Simulation	Error (%)
trj	ns	40.000	40.135	0.34

Reverse Recovery Characteristic Reference



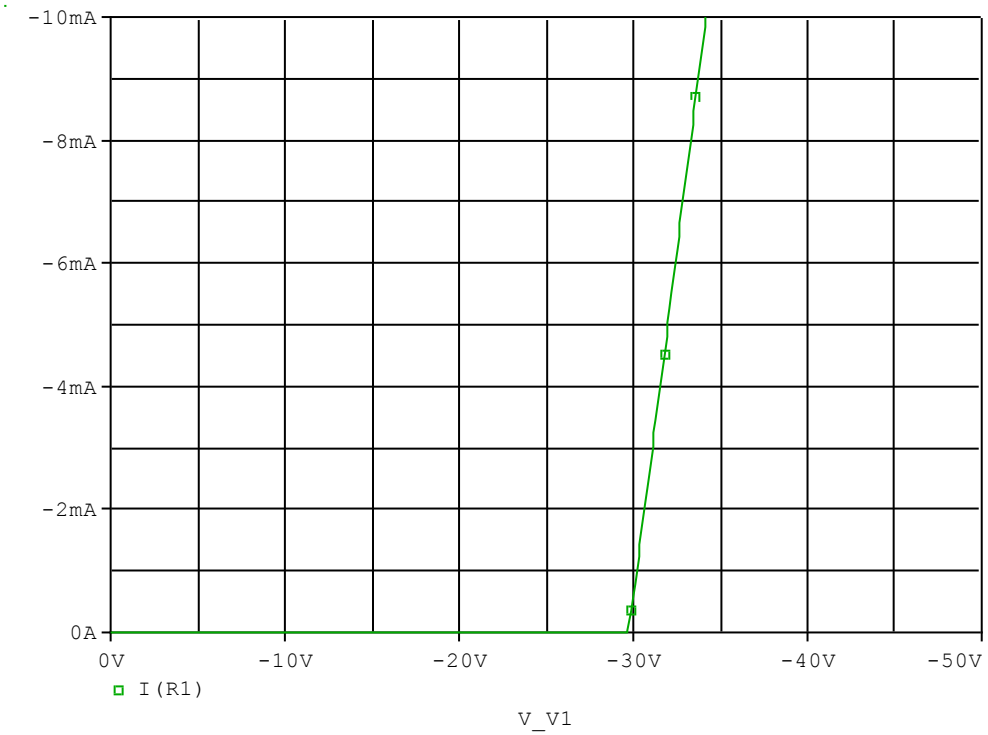
Trj=40.00(ns)
Trb=60.00(ns)
Conditions:Ifwd=Irev=0.2(A),Rl=50



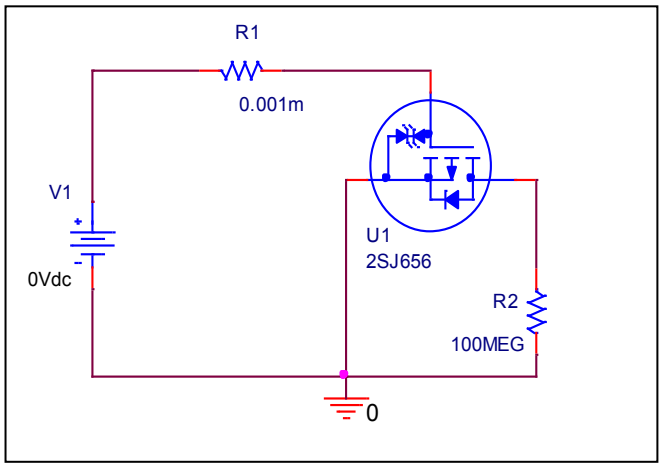
Relation between trj and trb

ESD PROTECTION DIODE SPICE MODEL
Zener Voltage Characteristic

Circuit Simulation Result



Evaluation Circuit



Zener Voltage Characteristic Reference